

S E R V I C E N O T E

SUPERSEDES: NONE

HP E3101A 4070 Series Semiconductor Parametric Tester**Serial Numbers:** JP10D00101 / JP10D00149**Firmware Update To Fix the Diag Leak Test Fail****To Be Performed By:** HP-Qualified Personnel**Parts Required:** None**Situation:**

Diag Leak Test intermittently fails with testhead firmware 1.04 (about 4 nA leak is detected for 3 nA test limit). The cause is that the bug of testhead firmware 1.04.

This problem also affects the application which has same measurement as Diag Leak Test.

Solution / Action:

The testhead firmware revision 1.05 was released. To fix the problem, update the testhead firmware to revision 1.05. HP customer engineer can go to customer site to update the firm-ware, and can bill the cost to the HSTD.

To get the software update image, go to the following files in our FTP server:

hpyidmk.jpn.hp.com(15.74.51.51)
~ftp/dist/dc_para/4070/th-fw/fw1.05.bin.Z

About how to download the testhead firmware binary, see "download" file in the same direc-tory.

About new features and fixed bugs, see "fw-history" file in the same directory.

About how to update the testhead firmware, see "update-fw-1.05" file in the same directory.

DATE: July 1997

ADMINISTRATIVE INFORMATION

SERVICE NOTE CLASSIFICATION:			
MODIFICATION RECOMMENDED			
ACTION CATEGORY:	<input checked="" type="checkbox"/> IMMEDIATELY <input type="checkbox"/> ON SPECIFIED FAILURE <input type="checkbox"/> AGREEABLE TIME	STANDARDS:	LABOR 0.5 Hours
LOCATION CATEGORY:	<input type="checkbox"/> CUSTOMER INSTALLABLE <input checked="" type="checkbox"/> ON-SITE <input type="checkbox"/> HP LOCATION	SERVICE INVENTORY:	<input type="checkbox"/> RETURN <input type="checkbox"/> SCRAP <input type="checkbox"/> SEE TEXT
AVAILABILITY:	PRODUCT'S SUPPORT LIFE	USED PARTS:	<input type="checkbox"/> RETURN <input type="checkbox"/> SCRAP <input type="checkbox"/> SEE TEXT
AUTHOR: SY	ENTITY: 3301	HP RESPONSIBLE UNTIL: July 1999	
		ADDITIONAL INFORMATION:	